Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/560,584	TASHIRO ET AL.	
Examiner	Art Unit	
Ann Y. Lam	1641	

SEARCHED					
Class	Subclass	Date	Examiner		
436 427 935	518 50 58 7.952.1 285.2 287.1 eod only	128 (05)			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
last search	5/28/07	2	
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